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What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M3
Core Size	32-Bit Single-Core
Speed	67MHz
Connectivity	I ² C, LINbus, SPI, UART/USART, USB
Peripherals	CapSense, DMA, LCD, POR, PWM, WDT
Number of I/O	38
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	2K x 8
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 5.5V
Data Converters	A/D 1x20b, 1x12b; D/A 4x8b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	68-VFQFN Exposed Pad
Supplier Device Package	68-QFN (8x8)
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/cy8c5866lti-lp022

Table 2-2 shows the pinout for the 99-pin CSP package. Since there are four V_{DDIO} pins, the set of I/O pins associated with any V_{DDIO} may sink up to 100 mA total, same as for the 100-pin and 68-pin devices.

Table 2-2. CSP Pinout

Ball	Name	Ball	Name	Ball	Name	Ball	Name
E5	P2[5]	L2	VIO1	B2	P3[6]	C8	VIO0
G6	P2[6]	K2	P1[6]	B3	P3[7]	D7	P0[4]
G5	P2[7]	C9	P4[2]	C3	P12[0]	E7	P0[5]
H6	P12[4]	E8	P4[3]	C4	P12[1]	B9	P0[6]
K7	P12[5]	K1	P1[7]	E3	P15[2]	D8	P0[7]
L8	P6[4]	H2	P12[6]	E4	P15[3]	D9	P4[4]
J6	P6[5]	F4	P12[7]	A1	NC	F8	P4[5]
H5	P6[6]	J1	P5[4]	A9	NC	F7	P4[6]
J5	P6[7]	H1	P5[5]	L1	NC	E6	P4[7]
L7	VSSB	F3	P5[6]	L9	NC	E9	VCCD
K6	Ind	G1	P5[7]	A3	VCCA	F9	VSSD
L6	VBOOST	G2	P15[6]	A4	VSSA	G9	VDDD
K5	VBAT	F2	P15[7]	B7	VSSA	H9	P6[0]
L5	VSSD	E2	VDDD	B8	VSSA	G8	P6[1]
L4	XRES	F1	VSSD	C7	VSSA	H8	P6[2]
J4	P5[0]	E1	VCCD	A5	VDDA	J9	P6[3]
K4	P5[1]	D1	P15[0]	A6	VSSD	G7	P15[4]
K3	P5[2]	D2	P15[1]	B5	P12[2]	F6	P15[5]
L3	P5[3]	C1	P3[0]	A7	P12[3]	F5	P2[0]
H4	P1[0]	C2	P3[1]	C5	P4[0]	J7	P2[1]
J3	P1[1]	D3	P3[2]	D5	P4[1]	J8	P2[2]
H3	P1[2]	D4	P3[3]	B6	P0[0]	K9	P2[3]
J2	P1[3]	B4	P3[4]	C6	P0[1]	H7	P2[4]
G4	P1[4]	A2	P3[5]	A8	P0[2]	K8	VIO2
G3	P1[5]	B1	VIO3	D6	P0[3]		

Figure 2-5 on page 10 and Figure 2-6 on page 11 show an example schematic and an example PCB layout, for the 100-pin TQFP part, for optimal analog performance on a two-layer board.

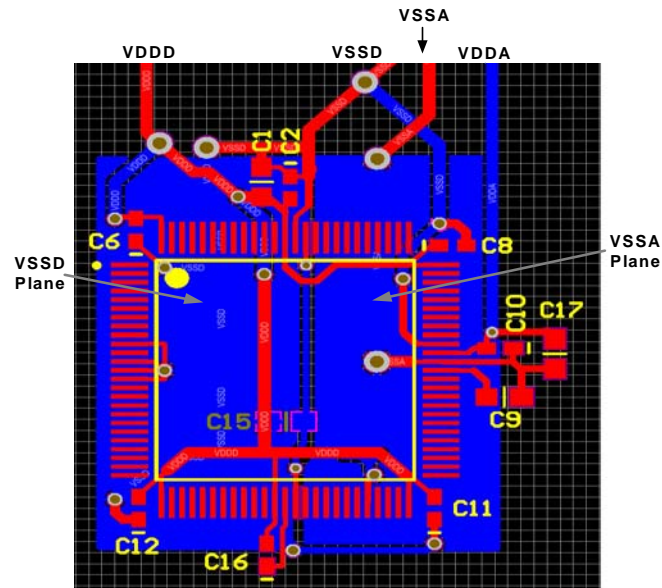
- The two pins labeled VDDD must be connected together.
- The two pins labeled VCCD must be connected together, with capacitance added, as shown in Figure 2-5 and Power System on page 26. The trace between the two VCCD pins should be as short as possible.
- The two pins labeled VSSD must be connected together.

For information on circuit board layout issues for mixed signals, refer to the application note, [AN57821 - Mixed Signal Circuit Board Layout Considerations for PSoC® 3 and PSoC 5](#).

Note

6. Pins are Do Not Use (DNU) on devices without USB. The pin must be left floating.

Figure 2-6. Example PCB Layout for 100-pin TQFP Part for Optimal Analog Performance



3. Pin Descriptions

IDAC0, IDAC1, IDAC2, IDAC3. Low-resistance output pin for high-current DACs (IDAC).

Opamp0out, Opamp1out, Opamp2out, Opamp3out. High current output of uncommitted opamp.^[7]

Extref0, Extref1. External reference input to the analog system.

SAR0 EXTREF, SAR1 EXTREF. External references for SAR ADCs

Opamp0-, Opamp1-, Opamp2-, Opamp3-. Inverting input to uncommitted opamp.

Opamp0+, Opamp1+, Opamp2+, Opamp3+. Noninverting input to uncommitted opamp.

GPIO. Provides interfaces to the CPU, digital peripherals, analog peripherals, interrupts, LCD segment drive, and CapSense.^[7]

I2C0: SCL, I2C1: SCL. I²C SCL line providing wake from sleep on an address match. Any I/O pin can be used for I²C SCL if wake from sleep is not required.

I2C0: SDA, I2C1: SDA. I²C SDA line providing wake from sleep on an address match. Any I/O pin can be used for I²C SDA if wake from sleep is not required.

Ind. Inductor connection to boost pump.

kHz XTAL: Xo, kHz XTAL: Xi. 32.768-kHz crystal oscillator pin.

MHz XTAL: Xo, MHz XTAL: Xi. 4 to 25-MHz crystal oscillator pin.

nTRST. Optional JTAG Test Reset programming and debug port connection to reset the JTAG connection.

SIO. Provides interfaces to the CPU, digital peripherals and interrupts with a programmable high threshold voltage, analog comparator, high sink current, and high impedance state when the device is unpowered.

SWDCK. SWD Clock programming and debug port connection.

SWDIO. SWD Input and Output programming and debug port connection.

TCK. JTAG Test Clock programming and debug port connection.

TDI. JTAG Test Data In programming and debug port connection.

TDO. JTAG Test Data Out programming and debug port connection.

TMS. JTAG Test Mode Select programming and debug port connection.

TRACECLK. Cortex-M3 TRACEPORT connection, clocks TRACEDATA pins.

TRACEDATA[3:0]. Cortex-M3 TRACEPORT connections, output data.

SWV. SWV output.

USBIO, D+. Provides D+ connection directly to a USB 2.0 bus. May be used as a digital I/O pin; it is powered from VDDD instead of from a VDDIO. Pins are Do Not Use (DNU) on devices without USB.

USBIO, D-. Provides D- connection directly to a USB 2.0 bus. May be used as a digital I/O pin; it is powered from VDDD instead of from a VDDIO. Pins are Do Not Use (DNU) on devices without USB.

VBOOST. Power sense connection to boost pump.

VBAT. Battery supply to boost pump.

VCCA. Output of the analog core regulator or the input to the analog core. Requires a 1uF capacitor to VSSA. The regulator output is not designed to drive external circuits. **Note that if you use the device with an external core regulator (externally regulated mode), the voltage applied to this pin must not exceed the allowable range of 1.71 V to 1.89 V.** When using the internal core regulator, (internally regulated mode, the default), do not tie any power to this pin. For details see [Power System](#) on page 26.

VCCD. Output of the digital core regulator or the input to the digital core. The two VCCD pins must be shorted together, with the trace between them as short as possible, and a 1uF capacitor to VSSD. The regulator output is not designed to drive external circuits. **Note that if you use the device with an external core regulator (externally regulated mode), the voltage applied to this pin must not exceed the allowable range of 1.71 V to 1.89 V.** When using the internal core regulator (internally regulated mode, the default), do not tie any power to this pin. For details see [Power System](#) on page 26.

VDDA. Supply for all analog peripherals and analog core regulator. **VDDA must be the highest voltage present on the device. All other supply pins must be less than or equal to VDDA.**

VDDD. Supply for all digital peripherals and digital core regulator. VDDD must be less than or equal to VDDA.

VSSA. Ground for all analog peripherals.

VSSB. Ground connection for boost pump.

VSSD. Ground for all digital logic and I/O pins.

VDDIO0, VDDIO1, VDDIO2, VDDIO3. Supply for I/O pins. Each VDDIO must be tied to a valid operating voltage (1.71 V to 5.5 V), and must be less than or equal to VDDA.

XRES. External reset pin. Active low with internal pull-up.

Note

7. GPIOs with opamp outputs are not recommended for use with CapSense.

5. Memory

5.1 Static RAM

CY8C58LP static RAM (SRAM) is used for temporary data storage. Code can be executed at full speed from the portion of SRAM that is located in the code space. This process is slower from SRAM above 0x20000000. The device provides up to 64 KB of SRAM. The CPU or the DMA controller can access all of SRAM. The SRAM can be accessed simultaneously by the Cortex-M3 CPU and the DMA controller if accessing different 32-KB blocks.

5.2 Flash Program Memory

Flash memory in PSoC devices provides nonvolatile storage for user firmware, user configuration data, bulk data storage, and optional ECC data. The main flash memory area contains up to 256 KB of user program space.

Up to an additional 32 KB of flash space is available for Error Correcting Codes (ECC). If ECC is not used this space can store device configuration data and bulk user data. User code may not be run out of the ECC flash memory section. ECC can correct one bit error and detect two bit errors per 8 bytes of firmware memory; an interrupt can be generated when an error is detected. The flash output is 9 bytes wide with 8 bytes of data and 1 byte of ECC data.

The CPU or DMA controller read both user code and bulk data located in flash through the cache controller. This provides higher CPU performance. If ECC is enabled, the cache controller also performs error checking and correction.

Flash programming is performed through a special interface and preempts code execution out of flash. Code execution may be done out of SRAM during flash programming.

The flash 24programming interface performs flash erasing, programming and setting code protection levels. Flash in-system serial programming (ISSP), typically used for production programming, is possible through both the SWD and JTAG interfaces. In-system programming, typically used for bootloaders, is also possible using serial interfaces such as I²C, USB, UART, and SPI, or any communications protocol.

5.3 Flash Security

All PSoC devices include a flexible flash protection model that prevents access and visibility to on-chip flash memory. This prevents duplication or reverse engineering of proprietary code. Flash memory is organized in blocks, where each block contains 256 bytes of program or data and 32 bytes of ECC or configuration data.

The device offers the ability to assign one of four protection levels to each row of flash. [Table 5-1](#) lists the protection modes available. Flash protection levels can only be changed by performing a complete flash erase. The Full Protection and Field Upgrade settings disable external access (through a debugging tool such as PSoC Creator, for example). If your application requires code update through a boot loader, then use the Field Upgrade setting. Use the Unprotected setting only when no security is needed in your application. The PSoC device also offers an advanced security feature called Device Security which permanently disables all test, programming, and debug ports, protecting your application from external access (see the

“Device Security” section on page 64). For more information on how to take full advantage of the security features in PSoC, see the PSoC 5 TRM.

Table 5-1. Flash Protection

Protection Setting	Allowed	Not Allowed
Unprotected	External read and write + internal read and write	–
Factory Upgrade	External write + internal read and write	External read
Field Upgrade	Internal read and write	External read and write
Full Protection	Internal read	External read and write + internal write

Disclaimer

Note the following details of the flash code protection features on Cypress devices.

Cypress products meet the specifications contained in their particular Cypress datasheets. Cypress believes that its family of products is one of the most secure families of its kind on the market today, regardless of how they are used. There may be methods, unknown to Cypress, that can breach the code protection features. Any of these methods, to our knowledge, would be dishonest and possibly illegal. Neither Cypress nor any other semiconductor manufacturer can guarantee the security of their code. Code protection does not mean that we are guaranteeing the product as “unbreakable.”

Cypress is willing to work with the customer who is concerned about the integrity of their code. Code protection is constantly evolving. We at Cypress are committed to continuously improving the code protection features of our products.

5.4 EEPROM

PSoC EEPROM memory is a byte addressable nonvolatile memory. The CY8C58LP has 2 KB of EEPROM memory to store user data. Reads from EEPROM are random access at the byte level. Reads are done directly; writes are done by sending write commands to an EEPROM programming interface. CPU code execution can continue from flash during EEPROM writes. EEPROM is erasable and writeable at the row level. The EEPROM is divided into 128 rows of 16 bytes each. The factory default values of all EEPROM bytes are 0.

Because the EEPROM is mapped to the Cortex-M3 Peripheral region, the CPU cannot execute out of EEPROM. There is no ECC hardware associated with EEPROM. If ECC is required it must be handled in firmware.

It can take as much as 20 milliseconds to write to EEPROM or flash. During this time the device should not be reset, or unexpected changes may be made to portions of EEPROM or flash. Reset sources (see [Reset Sources](#) on page 32) include XRES pin, software reset, and watchdog; care should be taken to make sure that these are not inadvertently activated. In addition, the low voltage detect circuits should be configured to generate an interrupt instead of a reset.

7.2.2.3 Conditionals

Each datapath has two compares, with bit masking options. Compare operands include the two accumulators and the two data registers in a variety of configurations. Other conditions include zero detect, all ones detect, and overflow. These conditions are the primary datapath outputs, a selection of which can be driven out to the UDB routing matrix. Conditional computation can use the built in chaining to neighboring UDBs to operate on wider data widths without the need to use routing resources.

7.2.2.4 Variable MSB

The most significant bit of an arithmetic and shift function can be programmatically specified. This supports variable width CRC and PRS functions, and in conjunction with ALU output masking, can implement arbitrary width timers, counters and shift blocks.

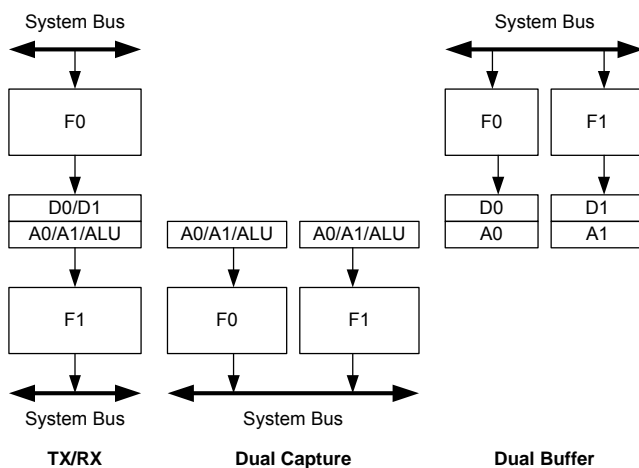
7.2.2.5 Built-in CRC/PRS

The datapath has built in support for single cycle Cyclic Redundancy Check (CRC) computation and Pseudo Random Sequence (PRS) generation of arbitrary width and arbitrary polynomial. CRC/PRS functions longer than 8 bits may be implemented in conjunction with PLD logic, or built in chaining may be used to extend the function into neighboring UDBs.

7.2.2.6 Input/Output FIFOs

Each datapath contains two four-byte deep FIFOs, which can be independently configured as an input buffer (system bus writes to the FIFO, datapath internal reads the FIFO), or an output buffer (datapath internal writes to the FIFO, the system bus reads from the FIFO). The FIFOs generate status that are selectable as datapath outputs and can therefore be driven to the routing, to interact with sequencers, interrupts, or DMA.

Figure 7-5. Example FIFO Configurations



7.2.2.7 Chaining

The datapath can be configured to chain conditions and signals such as carries and shift data with neighboring datapaths to create higher precision arithmetic, shift, CRC/PRS functions.

7.2.2.8 Time Multiplexing

In applications that are over sampled, or do not need high clock rates, the single ALU block in the datapath can be efficiently shared with two sets of registers and condition generators. Carry and shift out data from the ALU are registered and can be selected as inputs in subsequent cycles. This provides support for 16-bit functions in one (8-bit) datapath.

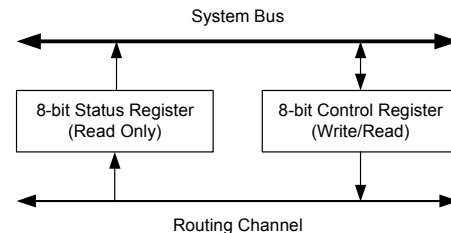
7.2.2.9 Datapath I/O

There are six inputs and six outputs that connect the datapath to the routing matrix. Inputs from the routing provide the configuration for the datapath operation to perform in each cycle, and the serial data inputs. Inputs can be routed from other UDB blocks, other device peripherals, device I/O pins, and so on. The outputs to the routing can be selected from the generated conditions, and the serial data outputs. Outputs can be routed to other UDB blocks, device peripherals, interrupt and DMA controller, I/O pins, and so on.

7.2.3 Status and Control Module

The primary purpose of this circuitry is to coordinate CPU firmware interaction with internal UDB operation.

Figure 7-6. Status and Control Registers



The bits of the control register, which may be written to by the system bus, are used to drive into the routing matrix, and thus provide firmware with the opportunity to control the state of UDB processing. The status register is read-only and it allows internal UDB state to be read out onto the system bus directly from internal routing. This allows firmware to monitor the state of UDB processing. Each bit of these registers has programmable connections to the routing matrix and routing connections are made depending on the requirements of the application.

7.2.3.1 Usage Examples

As an example of control input, a bit in the control register can be allocated as a function enable bit. There are multiple ways to enable a function. In one method the control bit output would be routed to the clock control block in one or more UDBs and serve as a clock enable for the selected UDB blocks. A status example is a case where a PLD or datapath block generated a condition, such as a "compare true" condition that is captured and latched by the status register and then read (and cleared) by CPU firmware.

7.2.3.2 Clock Generation

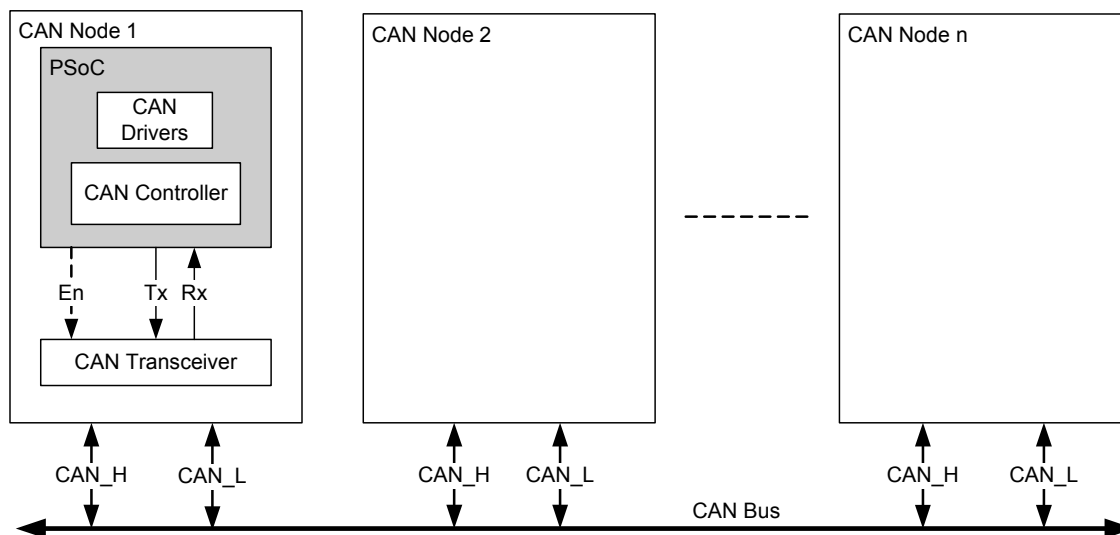
Each subcomponent block of a UDB including the two PLDs, the datapath, and Status and Control, has a clock selection and control block. This promotes a fine granularity with respect to allocating clocking resources to UDB component blocks and allows unused UDB resources to be used by other functions for maximum system efficiency.

7.5 CAN

The CAN peripheral is a fully functional Controller Area Network (CAN) supporting communication baud rates up to 1 Mbps. The CAN controller implements the CAN2.0A and CAN2.0B specifications as defined in the Bosch specification and conforms to the ISO-11898-1 standard. The CAN protocol was originally designed for automotive applications with a focus on a high level of fault detection. This ensures high communication

reliability at a low cost. Because of its success in automotive applications, CAN is used as a standard communication protocol for motion oriented machine control networks (CANOpen) and factory automation applications (DeviceNet). The CAN controller features allow the efficient implementation of higher level protocols without affecting the performance of the microcontroller CPU. Full configuration support is provided in PSoC Creator.

Figure 7-14. CAN Bus System Implementation



7.5.1 CAN Features

- CAN2.0A/B protocol implementation - ISO 11898 compliant
 - Standard and extended frames with up to 8 bytes of data per frame
 - Message filter capabilities
 - Remote Transmission Request (RTR) support
 - Programmable bit rate up to 1 Mbps
- Listen Only mode
- SW readable error counter and indicator
- Sleep mode: Wake the device from sleep with activity on the Rx pin
- Supports two or three wire interface to external transceiver (Tx, Rx, and Enable). The three-wire interface is compatible with the Philips PHY; the PHY is not included on-chip. The three wires can be routed to any I/O
- Enhanced interrupt controller
 - CAN receive and transmit buffers status
 - CAN controller error status including BusOff

- Receive path
 - 16 receive buffers each with its own message filter
 - Enhanced hardware message filter implementation that covers the ID, IDE and RTR
 - DeviceNet addressing support
 - Multiple receive buffers linkable to build a larger receive message array
 - Automatic transmission request (RTR) response handler
 - Lost received message notification
- Transmit path
 - Eight transmit buffers
 - Programmable transmit priority
 - Round robin
 - Fixed priority
 - Message transmissions abort capability

7.5.2 Software Tools Support

CAN Controller configuration integrated into PSoC Creator:

- CAN Configuration walkthrough with bit timing analyzer
- Receive filter setup

9.8 CSP Package Bootloader

A factory-installed bootloader program is included in all devices with CSP packages. The bootloader is compatible with PSoC Creator 3.0 bootloadable project files, and has the following features:

- I2C-based
 - SCLK and SDAT available at P1[6] and P1[7], respectively
 - External pull-up resistors required
 - I2C slave, address 4, data rate = 100 kbps
 - Single application
 - Wait 2 seconds for bootload command
- Other bootloader options are as set by the PSoC Creator 3.0 Bootloader Component default
 - Occupies the bottom 9 Kbytes of flash

For more information on this bootloader, see the following Cypress application notes:

■ AN73854, PSoC 3 and PSoC 5 LP Introduction to Bootloaders

■ AN60317, PSoC 3 and PSoC 5 LP I2C Bootloader

Note that a PSoC Creator bootloadable project must be associated with .hex and .elf files for a bootloader project that is configured for the target device. Bootloader .hex and .elf files can be found at www.cypress.com/go/PSOC5LPdatasheet.

The factory-installed bootloader can be overwritten using JTAG or SWD programming.

11. Electrical Specifications

Specifications are valid for $-40\text{ }^{\circ}\text{C} \leq T_A \leq 105\text{ }^{\circ}\text{C}$ and $T_J \leq 120\text{ }^{\circ}\text{C}$, except where noted. Specifications are valid for 1.71 V to 5.5 V, except where noted. The unique flexibility of the PSoC UDBs and analog blocks enable many functions to be implemented in PSoC Creator components, see the component datasheets for full AC/DC specifications of individual functions. See the [Example Peripherals](#) on page 40 for further explanation of PSoC Creator components.

11.1 Absolute Maximum Ratings

Table 11-1. Absolute Maximum Ratings DC Specifications^[14]

Parameter	Description	Conditions	Min	Typ	Max	Units
V_{DDA}	Analog supply voltage relative to V_{SSA}		-0.5	–	6	V
V_{DDD}	Digital supply voltage relative to V_{SSD}		-0.5	–	6	V
V_{DDIO}	I/O supply voltage relative to V_{SSD}		-0.5	–	6	V
V_{CCA}	Direct analog core voltage input		-0.5	–	1.95	V
V_{CCD}	Direct digital core voltage input		-0.5	–	1.95	V
V_{SSA}	Analog ground voltage		$V_{SSD} - 0.5$	–	$V_{SSD} + 0.5$	V
$V_{GPIO}^{[15]}$	DC input voltage on GPIO	Includes signals sourced by V_{DDA} and routed internal to the pin.	$V_{SSD} - 0.5$	–	$V_{DDIO} + 0.5$	V
V_{SIO}	DC input voltage on SIO	Output disabled	$V_{SSD} - 0.5$	–	7	V
		Output enabled	$V_{SSD} - 0.5$	–	6	V
V_{IND}	Voltage at boost converter input		0.5	–	5.5	V
V_{BAT}	Boost converter supply		$V_{SSD} - 0.5$	–	5.5	V
I_{VDDIO}	Current per V_{DDIO} supply pin		–	–	100	mA
I_{GPIO}	GPIO current		-30	–	41	mA
I_{SIO}	SIO current		-49	–	28	mA
I_{USBIO}	USBIO current		-56	–	59	mA
V_{EXTREF}	ADC external reference inputs	Pins P0[3], P3[2]	–	–	2	V
LU	Latch up current ^[16]		-140	–	140	mA
ESD_{HBM}	Electrostatic discharge voltage	Human body model	2000	–	–	V
ESD_{CDM}	ESD voltage	Charge device model	500	–	–	V

Notes

14. Usage above the absolute maximum conditions listed in [Table 11-1](#) may cause permanent damage to the device. Exposure to Absolute Maximum conditions for extended periods of time may affect device reliability. The Maximum Storage Temperature is 150 °C in compliance with JEDEC Standard JESD22-A103, High Temperature Storage Life. When used below Absolute Maximum conditions but above normal operating conditions, the device may not operate to specification.

15. The V_{DDIO} supply voltage must be greater than the maximum voltage on the associated GPIO pins. Maximum voltage on GPIO pin $\leq V_{DDIO} \leq V_{DDA}$.

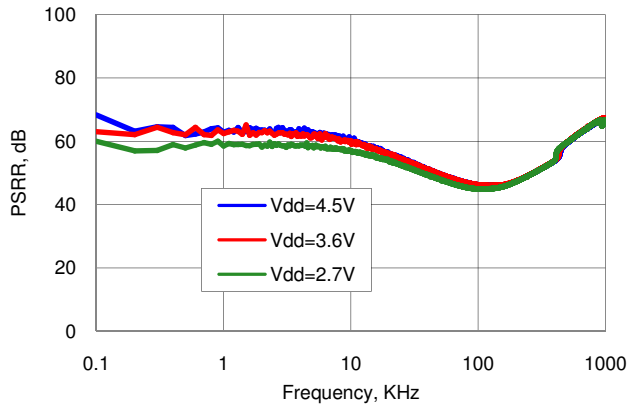
16. Meets or exceeds JEDEC Spec EIA/JESD78 IC Latch-up Test.

11.3.2 Analog Core Regulator

Table 11-5. Analog Core Regulator DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
V _{DDA}	Input voltage		1.8	–	5.5	V
V _{CCA}	Output voltage		–	1.80	–	V
	Regulator output capacitor	±10%, X5R ceramic or better	0.9	1	1.1	μF

Figure 11-7. Analog Regulator PSRR vs Frequency and V_{DD}



11.3.3 Inductive Boost Regulator

Unless otherwise specified, operating conditions are: V_{BAT} = 0.5 V–3.6 V, V_{OUT} = 1.8 V–5.0 V, I_{OUT} = 0 mA–50 mA, L_{BOOST} = 4.7 μH–22 μH, C_{BOOST} = 22 μF || 3 × 1.0 μF || 3 × 0.1 μF, C_{BAT} = 22 μF, I_F = 1.0 A, excludes 99-pin CSP package. For information on using boost with 99-pin CSP package, contact Cypress support. Unless otherwise specified, all charts and graphs show typical values.

Table 11-6. Inductive Boost Regulator DC Specifications

Parameter	Description	Conditions		Min	Typ	Max	Units
V _{OUT}	Boost output voltage ^[29]	vsel = 1.8 V in register BOOST_CR0		1.71	1.8	1.89	V
		vsel = 1.9 V in register BOOST_CR0		1.81	1.90	2.00	V
		vsel = 2.0 V in register BOOST_CR0		1.90	2.00	2.10	V
		vsel = 2.4 V in register BOOST_CR0		2.16	2.40	2.64	V
		vsel = 2.7 V in register BOOST_CR0		2.43	2.70	2.97	V
		vsel = 3.0 V in register BOOST_CR0		2.70	3.00	3.30	V
		vsel = 3.3 V in register BOOST_CR0		2.97	3.30	3.63	V
		vsel = 3.6 V in register BOOST_CR0		3.24	3.60	3.96	V
		vsel = 5.0 V in register BOOST_CR0		4.50	5.00	5.50	V
V _{BAT}	Input voltage to boost ^[30]	I _{OUT} = 0 mA–5 mA	vsel = 1.8 V–2.0 V, T _A = 0 °C–70 °C	0.5	–	0.8	V
		I _{OUT} = 0 mA–15 mA	vsel = 1.8 V–5.0 V ^[31] , T _A = –10 °C–85 °C	1.6	–	3.6	V
		I _{OUT} = 0 mA–25 mA	vsel = 1.8 V–2.7 V, T _A = –10 °C–85 °C	0.8	–	1.6	V
		I _{OUT} = 0 mA–50 mA	vsel = 1.8 V–3.3 V ^[31] , T _A = –40 °C–85 °C	1.8	–	2.5	V
			vsel = 1.8 V–3.3 V ^[31] , T _A = –10 °C–85 °C	1.3	–	2.5	V
			vsel = 2.5 V–5.0 V ^[31] , T _A = –10 °C–85 °C	2.5	–	3.6	V

11.4 Inputs and Outputs

Specifications are valid for $-40\text{ }^{\circ}\text{C} \leq T_A \leq 105\text{ }^{\circ}\text{C}$ and $T_J \leq 120\text{ }^{\circ}\text{C}$, except where noted. Specifications are valid for 1.71 V to 5.5 V, except where noted. Unless otherwise specified, all charts and graphs show typical values.

When the power supplies ramp up, there are low-impedance connections between each GPIO pin and its V_{DDIO} supply. This causes the pin voltages to track V_{DDIO} until both V_{DDIO} and V_{DDA} reach the IPOR voltage, which can be as high as 1.45 V. At that point, the low-impedance connections no longer exist and the pins change to their normal NVL settings.

Also, if V_{DDA} is less than V_{DDIO} , a low-impedance path may exist between a GPIO and V_{DDA} , causing the GPIO to track V_{DDA} until V_{DDA} becomes greater than or equal to V_{DDIO} .

11.4.1 GPIO

Table 11-8. GPIO DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
V_{IH}	Input voltage high threshold	CMOS Input, $PRT[x]CTL = 0$	$0.7 \times V_{DDIO}$	—	—	V
V_{IL}	Input voltage low threshold	CMOS Input, $PRT[x]CTL = 0$	—	—	$0.3 \times V_{DDIO}$	V
V_{IH}	Input voltage high threshold	LVTTL Input, $PRT[x]CTL = 1$, $V_{DDIO} < 2.7\text{ V}$	$0.7 \times V_{DDIO}$	—	—	V
V_{IH}	Input voltage high threshold	LVTTL Input, $PRT[x]CTL = 1$, $V_{DDIO} \geq 2.7\text{ V}$	2.0	—	—	V
V_{IL}	Input voltage low threshold	LVTTL Input, $PRT[x]CTL = 1$, $V_{DDIO} < 2.7\text{ V}$	—	—	$0.3 \times V_{DDIO}$	V
V_{IL}	Input voltage low threshold	LVTTL Input, $PRT[x]CTL = 1$, $V_{DDIO} \geq 2.7\text{ V}$	—	—	0.8	V
V_{OH}	Output voltage high	$I_{OH} = 4\text{ mA}$ at 3.3 V_{DDIO}	$V_{DDIO} - 0.6$	—	—	V
		$I_{OH} = 1\text{ mA}$ at 1.8 V_{DDIO}	$V_{DDIO} - 0.5$	—	—	V
V_{OL}	Output voltage low	$I_{OL} = 8\text{ mA}$ at 3.3 V_{DDIO}	—	—	0.6	V
		$I_{OL} = 3\text{ mA}$ at 3.3 V_{DDIO}	—	—	0.4	V
		$I_{OL} = 4\text{ mA}$ at 1.8 V_{DDIO}	—	—	0.6	V
R_{pullup}	Pull-up resistor		3.5	5.6	8.5	k Ω
$R_{pulldown}$	Pull-down resistor		3.5	5.6	8.5	k Ω
I_{IL}	Input leakage current (absolute value) ^[34]	25 °C, $V_{DDIO} = 3.0\text{ V}$	—	—	2	nA
C_{IN}	Input capacitance ^[34]	P0.0, P0.1, P0.2, P3.6, P3.7	—	17	20	pF
		P0.3, P0.4, P3.0, P3.1, P3.2	—	10	15	pF
		P0.6, P0.7, P15.0, P15.6, P15.7 ^[35]	—	7	12	pF
		All other GPIOs	—	5	9	pF
V_H	Input voltage hysteresis (Schmitt-Trigger) ^[34]		—	40	—	mV
I_{diode}	Current through protection diode to V_{DDIO} and V_{SSIO}		—	—	100	μA
R_{global}	Resistance pin to analog global bus	25 °C, $V_{DDIO} = 3.0\text{ V}$	—	320	—	Ω
R_{mux}	Resistance pin to analog mux bus	25 °C, $V_{DDIO} = 3.0\text{ V}$	—	220	—	Ω

Notes

34. Based on device characterization (Not production tested).

35. For information on designing with PSoC oscillators, refer to the application note, [AN54439 - PSoC® 3 and PSoC 5 External Oscillator](#).

Figure 11-15. GPIO Output High Voltage and Current

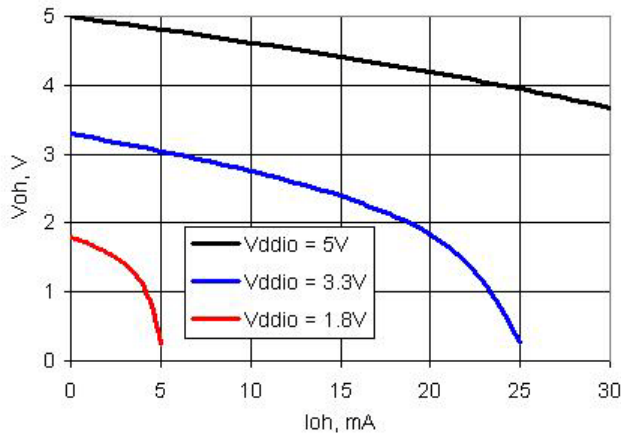


Figure 11-16. GPIO Output Low Voltage and Current

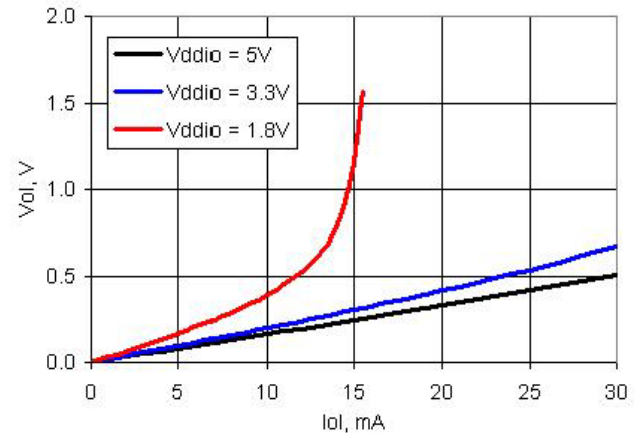
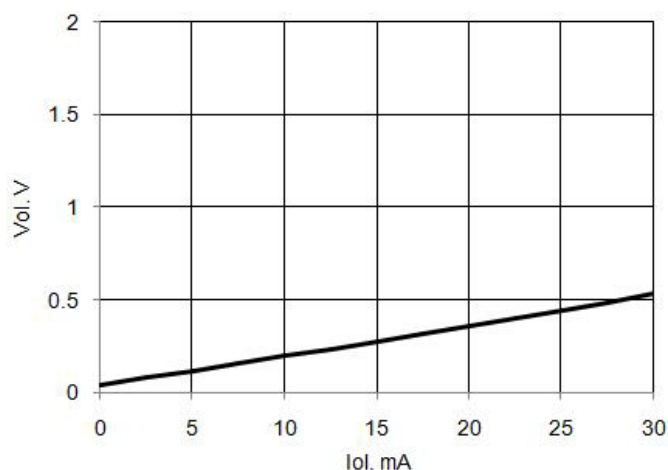


Table 11-9. GPIO AC Specifications^[36]

Parameter	Description	Conditions	Min	Typ	Max	Units
TriseF	Rise time in Fast Strong Mode	3.3 V V_{DDIO} Cload = 25 pF	–	–	6	ns
TfallF	Fall time in Fast Strong Mode	3.3 V V_{DDIO} Cload = 25 pF	–	–	6	ns
TriseS	Rise time in Slow Strong Mode	3.3 V V_{DDIO} Cload = 25 pF	–	–	60	ns
TfallS	Fall time in Slow Strong Mode	3.3 V V_{DDIO} Cload = 25 pF	–	–	60	ns
Fgpioout	GPIO output operating frequency					
	2.7 V $\leq V_{DDIO} \leq 5.5$ V, fast strong drive mode	90/10% V_{DDIO} into 25 pF	–	–	33	MHz
	1.71 V $\leq V_{DDIO} < 2.7$ V, fast strong drive mode	90/10% V_{DDIO} into 25 pF	–	–	20	MHz
	3.3 V $\leq V_{DDIO} \leq 5.5$ V, slow strong drive mode	90/10% V_{DDIO} into 25 pF	–	–	7	MHz
	1.71 V $\leq V_{DDIO} < 3.3$ V, slow strong drive mode	90/10% V_{DDIO} into 25 pF	–	–	3.5	MHz
Fgpioin	GPIO input operating frequency	90/10% V_{DDIO}	–	–	33	MHz

Note

36. Based on device characterization (Not production tested).

Figure 11-24. USBIO Output Low Voltage and Current, GPIO Mode

Table 11-15. USB Driver AC Specifications^[42]

Parameter	Description	Conditions	Min	Typ	Max	Units
Tr	Transition rise time		–	–	20	ns
Tf	Transition fall time		–	–	20	ns
TR	Rise/fall time matching	V _{USB_5} , V _{USB_3.3} , see USB DC Specifications on page 114	90%	–	111%	
Vcrs	Output signal crossover voltage		1.3	–	2	V

11.4.4 XRES

Table 11-16. XRES DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
V _{IH}	Input voltage high threshold		$0.7 \times V_{DDIO}$	–	–	V
V _{IL}	Input voltage low threshold		–	–	$0.3 \times V_{DDIO}$	V
Rpullup	Pull-up resistor		3.5	5.6	8.5	kΩ
C _{IN}	Input capacitance ^[42]		–	3		pF
V _H	Input voltage hysteresis (Schmitt-Trigger) ^[42]		–	100	–	mV
I _{diode}	Current through protection diode to V _{DDIO} and V _{SSIO}		–	–	100	μA

Table 11-17. XRES AC Specifications^[42]

Parameter	Description	Conditions	Min	Typ	Max	Units
T _{RESET}	Reset pulse width		1	–	–	μs

Note

42. Based on device characterization (Not production tested).

11.5.4 SAR ADC

Table 11-28. SAR ADC DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
	Resolution		–	–	12	bits
	Number of channels – single-ended		–	–	No of GPIO	
	Number of channels – differential	Differential pair is formed using a pair of neighboring GPIO.	–	–	No of GPIO/2	
	Monotonicity ^[52]		Yes	–	–	
Ge	Gain error ^[53]	External reference	–	–	±0.1	%
V _{OS}	Input offset voltage		–	–	±2	mV
I _{DD}	Current consumption ^[52]		–	–	1	mA
	Input voltage range – single-ended ^[52]		V _{SSA}	–	V _{DDA}	V
	Input voltage range – differential ^[52]		V _{SSA}	–	V _{DDA}	V
PSRR	Power supply rejection ratio ^[52]		70	–	–	dB
CMRR	Common mode rejection ratio		70	–	–	dB
INL	Integral non linearity ^[52]	V _{DDA} 1.71 to 5.5 V, 1 Msps, V _{REF} 1 to 5.5 V, bypassed at ExtRef pin	–	–	+2/–1.5	LSB
		V _{DDA} 2.0 to 3.6 V, 1 Msps, V _{REF} 2 to V _{DDA} , bypassed at ExtRef pin	–	–	±1.2	LSB
		V _{DDA} 1.71 to 5.5 V, 500 kps, V _{REF} 1 to 5.5 V, bypassed at ExtRef pin	–	–	±1.3	LSB
DNL	Differential non linearity ^[52]	V _{DDA} 1.71 to 5.5 V, 1 Msps, V _{REF} 1 to 5.5 V, bypassed at ExtRef pin	–	–	+2/–1	LSB
		V _{DDA} 2.0 to 3.6 V, 1 Msps, V _{REF} 2 to V _{DDA} , bypassed at ExtRef pin No missing codes	–	–	1.7/–0.99	LSB
		V _{DDA} 1.71 to 5.5 V, 500 kps, V _{REF} 1 to 5.5 V, bypassed at ExtRef pin No missing codes	–	–	+2/–0.99	LSB
R _{IN}	Input resistance ^[52]		–	180	–	kΩ

Notes

52. Based on device characterization (Not production tested).

53. For total analog system I_{dd} < 5 mA, depending on package used. With higher total analog system currents it is recommended that the SAR ADC be used in differential mode.

11.6.6 Digital Filter Block

Table 11-57. DFB DC Specifications^[78]

Parameter	Description	Conditions	Min	Typ	Max	Units
	DFB operating current	64-tap FIR at F_{DFB}				
		500 kHz (6.7 ksps)	–	0.16	0.27	mA
		1 MHz (13.4 ksps)	–	0.33	0.53	mA
		10 MHz (134 ksps)	–	3.3	5.3	mA
		48 MHz (644 ksps)	–	15.7	25.5	mA
		80 MHz (1.07 Msps)	–	26.0	42.5	mA

Table 11-58. DFB AC Specifications^[78]

Parameter	Description	Conditions	Min	Typ	Max	Units
F_{DFB}	DFB operating frequency		DC	–	80.01	MHz

11.6.7 USB

Table 11-59. USB DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
V_{USB_5}	Device supply (V_{DDD}) for USB operation	USB configured, USB regulator enabled	4.35	–	5.25	V
$V_{USB_3.3}$		USB configured, USB regulator bypassed	3.15	–	3.6	V
V_{USB_3}		USB configured, USB regulator bypassed ^[78]	2.85	–	3.6	V
$I_{USB_Configured}$	Device supply current in device active mode, bus clock and IMO = 24 MHz	$V_{DDD} = 5\text{ V}$, $F_{CPU} = 1.5\text{ MHz}$	–	10	–	mA
		$V_{DDD} = 3.3\text{ V}$, $F_{CPU} = 1.5\text{ MHz}$	–	8	–	mA
$I_{USB_Suspended}$	Device supply current in device sleep mode	$V_{DDD} = 5\text{ V}$, connected to USB host, PICU configured to wake on USB resume signal	–	0.5	–	mA
		$V_{DDD} = 5\text{ V}$, disconnected from USB host	–	0.3	–	mA
		$V_{DDD} = 3.3\text{ V}$, connected to USB host, PICU configured to wake on USB resume signal	–	0.5	–	mA
		$V_{DDD} = 3.3\text{ V}$, disconnected from USB host	–	0.3	–	mA

Note

78. Rise/fall time matching (TR) not guaranteed, see [Table 11-15 on page 84](#).

11.7 Memory

Specifications are valid for $-40\text{ }^{\circ}\text{C} \leq T_A \leq 105\text{ }^{\circ}\text{C}$ and $T_J \leq 120\text{ }^{\circ}\text{C}$, except where noted. Specifications are valid for 1.71 V to 5.5 V, except where noted.

11.7.1 Flash

Table 11-61. Flash DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
	Erase and program voltage	V_{DD} pin	1.71	–	5.5	V

Table 11-62. Flash AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
T_{WRITE}	Row write time (erase + program)		–	15	20	ms
T_{ERASE}	Row erase time		–	10	13	ms
	Row program time		–	5	7	ms
T_{BULK}	Bulk erase time (256 KB)		–	–	140	ms
	Sector erase time (16 KB)		–	–	15	ms
T_{PROG}	Total device programming time	No overhead ^[80]	–	5	7.5	seconds
	Flash data retention time, retention period measured from last erase cycle	Ambient temp. $T_A \leq 55\text{ }^{\circ}\text{C}$, 100 K erase/program cycles	20	–	–	years
		Ambient temp. $T_A \leq 85\text{ }^{\circ}\text{C}$, 10 K erase/program cycles	10	–	–	
		Ambient temp. $T_A \leq 105\text{ }^{\circ}\text{C}$, 10 K erase/program cycles, \leq one year at $T_A \geq 75\text{ }^{\circ}\text{C}$ ^[81]	10	–	–	

11.7.2 EEPROM

Table 11-63. EEPROM DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
	Erase and program voltage		1.71	–	5.5	V

Table 11-64. EEPROM AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
T_{WRITE}	Single row erase/write cycle time		–	10	20	ms
	EEPROM data retention time, retention period measured from last erase cycle	Ambient temp. $T_A \leq 25\text{ }^{\circ}\text{C}$, 1M erase/program cycles	20	–	–	years
		Ambient temp. $T_A \leq 55\text{ }^{\circ}\text{C}$, 100K erase/program cycles	20	–	–	
		Ambient temp. $T_A \leq 85\text{ }^{\circ}\text{C}$, 10K erase/program cycles	10	–	–	
		Ambient temp. $T_A \leq 105\text{ }^{\circ}\text{C}$, 10K erase/program cycles, \leq one year at $T_A \geq 75\text{ }^{\circ}\text{C}$ ^[81]	10	–	–	

Notes

80. See [PSoC 5 Device Programming Specifications](#) for a description of a low-overhead method of programming PSoC 5 flash.

81. Cypress provides a retention calculator to calculate the retention lifetime based on customers' individual temperature profiles for operation over the $-40\text{ }^{\circ}\text{C}$ to $+105\text{ }^{\circ}\text{C}$ ambient temperature range. Contact customercare@cypress.com.

11.8.5 SWD Interface

Figure 11-80. SWD Interface Timing

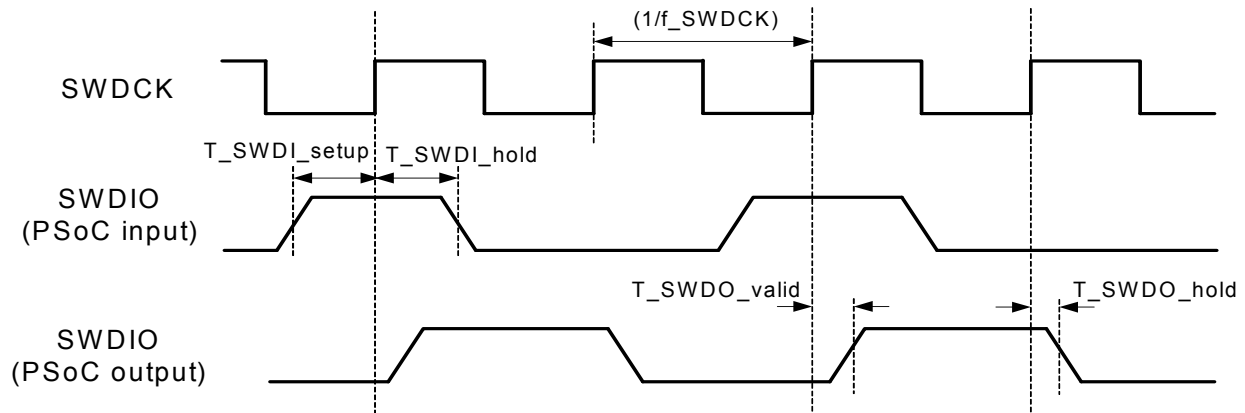


Table 11-77. SWD Interface AC Specifications^[95]

Parameter	Description	Conditions	Min	Typ	Max	Units
f_SWDCCK	SWDCLK frequency	$3.3\text{ V} \leq V_{\text{DDD}} \leq 5\text{ V}$	–	–	12 ^[96]	MHz
		$1.71\text{ V} \leq V_{\text{DDD}} < 3.3\text{ V}$	–	–	7 ^[96]	MHz
		$1.71\text{ V} \leq V_{\text{DDD}} < 3.3\text{ V}$, SWD over USBIO pins	–	–	5.5 ^[96]	MHz
T_SWDI_setup	SWDIO input setup before SWDCK high	$T = 1/f_{\text{SWDCCK}}$ max	T/4	–	–	
T_SWDI_hold	SWDIO input hold after SWDCK high	$T = 1/f_{\text{SWDCCK}}$ max	T/4	–	–	
T_SWDO_valid	SWDCK high to SWDIO output	$T = 1/f_{\text{SWDCCK}}$ max	–	–	T/2	
T_SWDO_hold	SWDIO output hold after SWDCK high	$T = 1/f_{\text{SWDCCK}}$ max	1	–	–	ns

11.8.6 TPIU Interface

Table 11-78. TPIU Interface AC Specifications^[95]

Parameter	Description	Conditions	Min	Typ	Max	Units
	TRACEPORT (TRACECLK) frequency		–	–	33 ^[97]	MHz
	SWV bit rate		–	–	33 ^[97]	Mbit

Notes

95. Based on device characterization (Not production tested).

96. f_SWDCCK must also be no more than 1/3 CPU clock frequency.

97. TRACEPORT signal frequency and bit rate are limited by GPIO output frequency, see [Table 11-9 on page 77](#).

11.9 Clocking

Specifications are valid for $-40\text{ }^{\circ}\text{C} \leq T_A \leq 105\text{ }^{\circ}\text{C}$ and $T_J \leq 120\text{ }^{\circ}\text{C}$, except where noted. Specifications are valid for 1.71 V to 5.5 V, except where noted. Unless otherwise specified, all charts and graphs show typical values

11.9.1 Internal Main Oscillator

Table 11-79. IMO DC Specifications^[98]

Parameter	Description	Conditions	Min	Typ	Max	Units
I _{cc_imo}	Supply current					
	74.7 MHz		–	–	730	μA
	62.6 MHz		–	–	600	μA
	48 MHz		–	–	500	μA
	24 MHz – USB mode	With oscillator locking to USB bus	–	–	500	μA
	24 MHz – non-USB mode		–	–	300	μA
	12 MHz		–	–	200	μA
	6 MHz		–	–	180	μA
	3 MHz		–	–	150	μA

Figure 11-81. IMO Current vs. Frequency

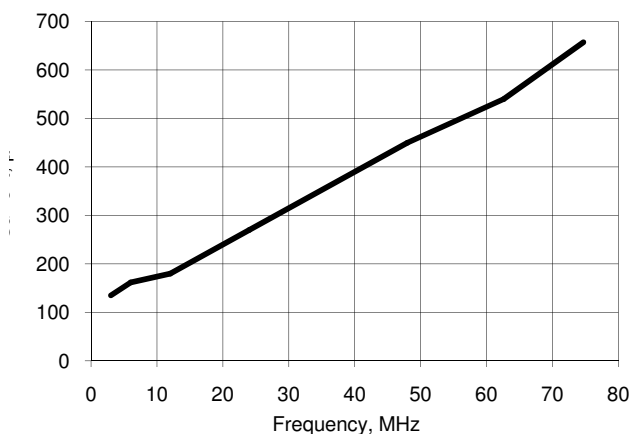


Table 11-80. IMO AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
F _{IMO} ^[99]	IMO frequency stability (with factory trim)					
	74.7 MHz		–7	–	7	%
	62.6 MHz		–7	–	7	%
	48 MHz		–5	–	5	%
	24 MHz – non-USB mode		–4	–	4	%
	24 MHz – USB mode	With oscillator locking to USB bus	–0.25	–	0.25	%
	12 MHz		–3	–	3	%
	6 MHz		–2	–	2	%
	3 MHz	0 °C to 70 °C	–1	–	1	%
		–40 °C to 105 °C	–1.5	–	1.5	%
	3-MHz frequency stability after typical PCB assembly post-reflow	Typical (non-optimized) board layout and 250 °C solder reflow. Device may be calibrated after assembly to improve performance.	–	±2%	–	%

Note

98. Based on device characterization (Not production tested).

11.9.3 MHz External Crystal Oscillator

For more information on crystal or ceramic resonator selection for the MHzECO, refer to application note [AN54439: PSoC 3 and PSoC 5 External Oscillators](#).

Table 11-83. MHzECO DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
I _{CC}	Operating current ^[104]	13.56 MHz crystal	–	3.8	–	mA

Table 11-84. MHzECO AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
F	Crystal frequency range		4	–	25	MHz

11.9.4 kHz External Crystal Oscillator

Table 11-85. kHzECO DC Specifications^[104]

Parameter	Description	Conditions	Min	Typ	Max	Units
I _{CC}	Operating current	Low power mode; CL = 6 pF	–	0.25	1.0	μA
DL	Drive level		–	–	1	μW

Table 11-86. kHzECO AC Specifications^[104]

Parameter	Description	Conditions	Min	Typ	Max	Units
F	Frequency		–	32.768	–	kHz
T _{ON}	Startup time	High power mode	–	1	–	s

11.9.5 External Clock Reference

Table 11-87. External Clock Reference AC Specifications^[104]

Parameter	Description	Conditions	Min	Typ	Max	Units
	External frequency range		0	–	33	MHz
	Input duty cycle range	Measured at V _{DDIO} /2	30	50	70	%
	Input edge rate	V _{IL} to V _{IH}	0.5	–	–	V/ns

11.9.6 Phase-Locked Loop

Table 11-88. PLL DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
I _{DD}	PLL operating current	In = 3 MHz, Out = 80 MHz	–	650	–	μA
		In = 3 MHz, Out = 67 MHz	–	400	–	μA
		In = 3 MHz, Out = 24 MHz	–	200	–	μA

Table 11-89. PLL AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
F _{plin}	PLL input frequency ^[105]		1	–	48	MHz
	PLL intermediate frequency ^[106]	Output of prescaler	1	–	3	MHz
F _{plout}	PLL output frequency ^[105]		24	–	80	MHz
	Lock time at startup		–	–	250	μs
J _{period-rms}	Jitter (rms) ^[104]		–	–	250	ps

Notes

¹⁰⁴.Based on device characterization (Not production tested).

¹⁰⁵.This specification is guaranteed by testing the PLL across the specified range using the IMO as the source for the PLL.

¹⁰⁶.PLL input divider, Q, must be set so that the input frequency is divided down to the intermediate frequency range. Value for Q ranges from 1 to 16.

12. Ordering Information

In addition to the features listed in [Table 12-1](#), every CY8C58LP device includes: up to 256 KB flash, 64 KB SRAM, 2 KB EEPROM, a precision on-chip voltage reference, precision oscillators, flash, ECC, DMA, a fixed function I²C, JTAG/SWD programming and debug, external memory interface, boost, and more. In addition to these features, the flexible UDBs and analog subsection support a wide range of peripherals. To assist you in selecting the ideal part, PSoC Creator makes a part recommendation after you choose the components required by your application. All CY8C58LP derivatives incorporate device and flash security in user-selectable security levels; see the TRM for details.

Table 12-1. CY8C58LP Family with ARM Cortex-M3 CPU

Part Number	MCU Core				Analog								Digital				I/O ^[109]				Package	JTAG ID ^[110]
	CPU SPEED (MHZ)	FLASH (KB)	SRAM (KB)	EEPROM (KB)	LCD SEGMENT DRIVE	ADCS	DAC	COMPARATORS	SC/CT ANALOG BLOCKS ^[107]	OPAMPS	DFB	CAPSENSE ^[108]	UDBS ^[108]	16-BIT TIMER/PWM	FS USB	CAN 2.0B	TOTAL I/O	GPIO	SIO	USBIO		
CY8C5868AXI-LP031	67	256	64	2	✓	1x20-bit Del-Sig 2x12-bit SAR	4	4	4	4	✓	✓	24	4	–	–	70	62	8	0	100-TQFP	0x2E11F069
CY8C5868AXI-LP032	67	256	64	2	✓	1x20-bit Del-Sig 2x12-bit SAR	4	4	4	4	✓	✓	24	4	✓	–	72	62	8	2	100-TQFP	0x2E120069
CY8C5868AXI-LP035	67	256	64	2	✓	1x20-bit Del-Sig 2x12-bit SAR	4	4	4	4	✓	✓	24	4	✓	✓	72	62	8	2	100-TQFP	0x2E123069
CY8C5868LTI-LP036	67	256	64	2	✓	1x20-bit Del-Sig 2x12-bit SAR	4	4	4	4	✓	✓	24	4	–	–	46	38	8	0	68-QFN	0x2E124069
CY8C5868LTI-LP038	67	256	64	2	✓	1x20-bit Del-Sig 2x12-bit SAR	4	4	4	4	✓	✓	24	4	✓	–	48	38	8	2	68-QFN	0x2E126069
CY8C5868LTI-LP039	67	256	64	2	✓	1x20-bit Del-Sig 2x12-bit SAR	4	4	4	4	✓	✓	24	4	✓	✓	48	38	8	2	68-QFN	0x2E127069
CY8C5867AXI-LP023	67	128	32	2	✓	1x20-bit Del-Sig 1x12-bit SAR	4	4	4	4	✓	✓	24	4	–	–	70	62	8	0	100-TQFP	0x2E117069
CY8C5867AXI-LP024	67	128	32	2	✓	1x20-bit Del-Sig 1x12-bit SAR	4	4	4	4	✓	✓	24	4	✓	–	72	62	8	2	100-TQFP	0x2E118069
CY8C5867LTI-LP025	67	128	32	2	✓	1x20-bit Del-Sig 1x12-bit SAR	4	4	4	4	✓	✓	24	4	–	–	46	38	8	0	68-QFN	0x2E119069
CY8C5867LTI-LP028	67	128	32	2	✓	1x20-bit Del-Sig 1x12-bit SAR	4	4	4	4	✓	✓	24	4	✓	–	48	38	8	2	68-QFN	0x2E11C069
CY8C5866AXI-LP020	67	64	16	2	✓	1x20-bit Del-Sig 1x12-bit SAR	4	4	4	4	✓	✓	20	4	✓	✓	72	62	8	2	100-TQFP	0x2E114069
CY8C5866AXI-LP021	67	64	16	2	✓	1x20-bit Del-Sig 1x12-bit SAR	4	4	4	4	✓	✓	20	4	✓	–	72	62	8	2	100-TQFP	0x2E115069
CY8C5866LTI-LP022	67	64	16	2	✓	1x20-bit Del-Sig 1x12-bit SAR	4	4	4	4	✓	✓	20	4	✓	–	48	38	8	2	68-QFN	0x2E116069
CY8C5888AXI-LP096	80	256	64	2	✓	1x20-bit Del-Sig 2x12-bit SAR	4	4	4	4	✓	✓	24	4	✓	✓	72	62	8	2	100-TQFP	0x2E160069
CY8C5888AXQ-LP096	80	256	64	2	✓	1x20-bit Del-Sig 2x12-bit SAR	4	4	4	4	✓	✓	24	4	✓	✓	72	62	8	2	100-TQFP	0x2E160069
CY8C5888LTI-LP097	80	256	64	2	✓	1x20-bit Del-Sig 2x12-bit SAR	4	4	4	4	✓	✓	24	4	✓	✓	48	38	8	2	68-QFN	0x2E161069
CY8C5888LTQ-LP097	80	256	64	2	✓	1x20-bit Del-Sig 2x12-bit SAR	4	4	4	4	✓	✓	24	4	✓	✓	48	38	8	2	68-QFN	0x2E161069
CY8C5888FNI-LP210	80	256	64	2	✓	1x20-bit Del-Sig 2x12-bit SAR	4	4	4	4	✓	✓	24	4	✓	✓	72	62	8	2	99-WLCSP	0x2E1D2069
CY8C5888FNI-LP214	80	256	64	2	✓	1x20-bit Del-Sig 2x12-bit SAR	4	4	4	4	✓	✓	24	4	✓	–	72	62	8	2	99-WLCSP	0x2E1D6069

Notes

107. Analog blocks support a wide variety of functionality including TIA, PGA, and mixers. See [Example Peripherals](#) on page 40 for more information on how analog blocks can be used.

108. UDBs support a wide variety of functionality including SPI, LIN, UART, timer, counter, PWM, PRS, and others. Individual functions may use a fraction of a UDB or multiple UDBs. Multiple functions can share a single UDB. See [Example Peripherals](#) on page 40 for more information on how UDBs can be used.

109. The I/O Count includes all types of digital I/O: GPIO, SIO, and the two USB I/O. See [I/O System and Routing](#) section on page 33 for details on the functionality of each of these types of I/O.

110. The JTAG ID has three major fields. The most significant nibble (left digit) is the version, followed by a 2 byte part number and a 3 nibble manufacturer ID.

Document History Page (continued)

Description Title: PSoC® 5LP: CY8C58LP Family Datasheet Programmable System-on-Chip (PSoC®) Document Number: 001-84932				
Revision	ECN	Orig. of Change	Submission Date	Description of Change
*H (cont.)	4698847	AVER / MKEA / GJV	03/24/2015	<p>Updated Electrical Specifications:</p> <p>Updated Memory:</p> <p>Updated Flash:</p> <p>Updated Table 11-62:</p> <p>Updated details in "Conditions" column corresponding to "Flash data retention time" parameter.</p> <p>Added Note 81 and referred the same note in last condition corresponding to "Flash data retention time" parameter.</p> <p>Updated EEPROM:</p> <p>Updated Table 11-64:</p> <p>Updated details in "Conditions" column corresponding to "EEPROM data retention time" parameter.</p> <p>Added Note 81 and referred the same note in last condition corresponding to "EEPROM data retention time" parameter.</p> <p>Updated Nonvolatile Latches (NVL):</p> <p>Updated Table 11-66:</p> <p>Updated details in "Conditions" column corresponding to "NVL data retention time" parameter.</p> <p>Added Note 82 and referred the same note in last condition corresponding to "NVL data retention time" parameter.</p> <p>Updated Clocking:</p> <p>Updated Internal Main Oscillator:</p> <p>Updated Table 11-80:</p> <p>Replaced 85 °C with 105 °C.</p> <p>Updated Figure 11-83.</p> <p>Updated Ordering Information:</p> <p>Updated Table 12-1:</p> <p>Updated part numbers.</p> <p>Updated Part Numbering Conventions:</p> <p>Added "Q: Extended" as sub bullet under "g: Temperature Range".</p> <p>Updated Packaging:</p> <p>Updated Table 13-1:</p> <p>Changed maximum value of T_A parameter from 85 °C to 105 °C.</p> <p>Changed maximum value of T_J parameter from 100 °C to 120 °C.</p> <p>Updated :</p> <p>Updated :</p> <p>spec 001-88034 – Changed revision from ** to *A.</p>
*I	4839323	MKEA	07/15/2015	<p>Added reference to code examples in More Information.</p> <p>Updated typ value of T_{WRITE} from 2 to 10 in EEPROM AC specs table.</p> <p>Changed "Device supply for USB operation" to "Device supply (V_{DDD}) for USB operation" in USB DC Specifications.</p> <p>Clarified power supply sequencing and margin for V_{DDA} and V_{DDD}.</p> <p>Updated Serial Wire Debug Interface with limitations of debugging on Port 15.</p> <p>Updated Delta-sigma ADC DC Specifications</p>